

Notice of References Cited	Application/Control No. 10/501,331		Applicant(s)/Patent Under Reexamination MINECHIKA ET AL.	
	Examiner Kim-Kwok CHU		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,099,251	08-2006	Naoi et al.	369/53.13
*	B	US-7,006,419	02-2006	Yokoi, Kenya	369/59.11
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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